

#### N-Channel Enhancement Mode Power MOSFET

## **Description**

The RMD50N40DFV uses advanced trench technology and design to provide excellent  $R_{DS(ON)}$  with low gate charge. It can be used in a wide variety of applications.

#### **General Feature**

- $V_{DS} = 40V, I_D = 65A$   $R_{DS(ON)} < 7.5m\Omega @ V_{GS} = 10V$  (Typ:6.8mΩ)  $R_{DS(ON)} < 10m\Omega @ V_{GS} = 4.5V$  (Typ:8.5mΩ)
- Special process technology for high ESD capability
- High density cell design for ultra low Rdson
- Fully characterized Avalanche voltage and current
- Good stability and uniformity with high E<sub>AS</sub>
- Excellent package for good heat dissipation

### **Application**

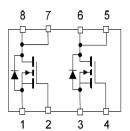
- Power switching application
- Hard switched and high frequency circuits
- Uninterruptible power supply
- Halogen-free
- P/N suffix V means AEC-Q101 qualified, e.g:RMD50N40DFV

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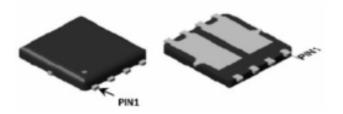
# Package Marking and Ordering Information

Device Marking	Device	Device Package	Reel Size	Tape width	Quantity
D50N40	RMD50N40DFV	DFN5X6-8L	-	-	-

Absolute Maximum Ratings (T <sub>C</sub> =25℃unless otherwise noted)				
Parameter	Symbol	Value	Unit	
Drain-Source Voltage	V <sub>DS</sub>	40	V	
Gate-Source Voltage	V <sub>GS</sub>	±20	V	
Continuous Drain Current (T <sub>a</sub> =25℃)	I <sub>D</sub>	65	Α	
Continuous Drain Current (T <sub>a</sub> =100℃)	I <sub>D</sub>	41	Α	
Pulsed Drain Currenr (1)	Ірм	260	Α	
Singel Pulsed Avalanche Energy (2)	Eas	96	mJ	
Power Dissipation	P <sub>D</sub>	48	W	
Thermal Resistance from Junction to Case (4)	Rejc	2.6	°C/W	
Thermal Resistance from Junction to Ambient (4)	R <sub>θJA</sub>	62	°C/W	
Junction Temperature	TJ	150	$^{\circ}$	
Storage Temperature	T <sub>STG</sub>	-55~ +150	$^{\circ}$	



#### Schematic diagram



Top View Bottom View

## Electrical Characteristics (T<sub>C</sub>=25°C unless otherwise noted)

Parameter	Symbol	Test Condition	Min	Туре	Max	Unit	
Static Characteristics							
Drain-source breakdown voltage	V <sub>(BR)DSS</sub>	V <sub>GS</sub> = 0V, I <sub>D</sub> =250μA	40	-	-	V	
Zero gate voltage drain current	I <sub>DSS</sub>	V <sub>DS</sub> =40V, V <sub>GS</sub> = 0V	-	-	1	μA	
Gate-body leakage current	lgss	V <sub>GS</sub> =±20V,V <sub>DS</sub> = 0V	-	-	±100	nA	
Gate threshold voltage <sup>(3)</sup>	V <sub>GS(th)</sub>	V <sub>DS</sub> =V <sub>GS</sub> , I <sub>D</sub> =250μA	1	1.5	2.5	V	
(2)		V <sub>GS</sub> =10V, I <sub>D</sub> =30A	-	6.8	7.5	0	
Drain-source on-resistance <sup>(3)</sup>	R <sub>DS(on)</sub>	V <sub>GS</sub> =4.5V, I <sub>D</sub> =20A	-	8.5	10	mΩ	
Dynamic characteristics							
Input Capacitance	Ciss		-	2956	-		
Output Capacitance	Coss	V <sub>DS</sub> =20V, V <sub>GS</sub> =0V, f =1MHz	-	225	-	pF	
Reverse Transfer Capacitance	Crss		-	197	-		
Switching characteristics							
Turn-on delay time	t <sub>d(on)</sub>		-	8	-		
Turn-on rise time	tr	$V_{DD}$ =20V, $I_D$ =30A, $R_L$ =1 $\Omega$	-	16	-		
Turn-off delay time	$\begin{array}{c ccccccccccccccccccccccccccccccccccc$	21	-	ns			
Turn-off fall time	t <sub>f</sub>		-	10	-		
Total Gate Charge	Qg	\/D0_00\/_ID_00A	-	46	-		
Gate-Source Charge	Qgs		-	7.2	-	nC	
Gate-Drain Charge	Qgd	- VGS=10V	-	8.8	-		
Source-Drain Diode characteristics	•	•	•	•			
Diode Forward voltage <sup>(3)</sup>	V <sub>DS</sub>	V <sub>GS</sub> =0V, I <sub>S</sub> =1A	-	-	1.2	V	
Diode Forward current <sup>(4)</sup>	Is		-	-	65	Α	

#### Notes:

- 1. Repetitive Rating: pulse width limited by maximum junction temperature
- 2. EAS Condition:TJ=25°C,VDD=20V,RG=25  $\Omega$  ,L=0.5mH
- 3. Pulse Test: pulse width≤300µs, duty cycle≤2%
- 4. Surface Mounted on FR4 Board,t≤10 sec



## **Test Circuit**

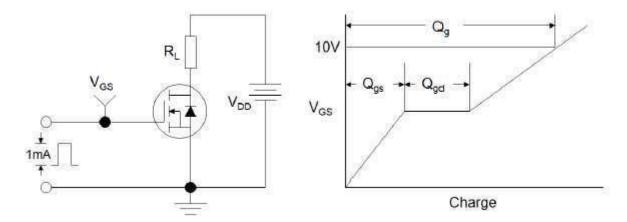


Figure1:Gate Charge Test Circuit & Waveform

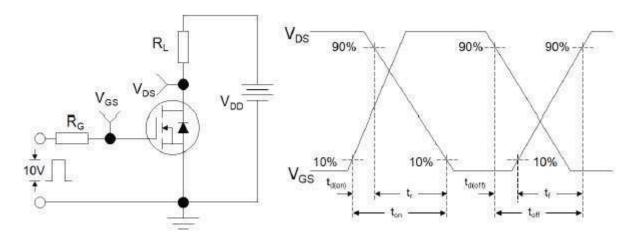


Figure 2: Resistive Switching Test Circuit & Waveforms

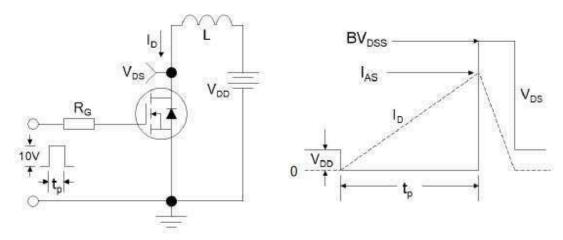


Figure 3:Unclamped Inductive Switching Test Circuit & Waveforms



## RATING AND CHARACTERISTICS CURVES (RMD50N40DFV)

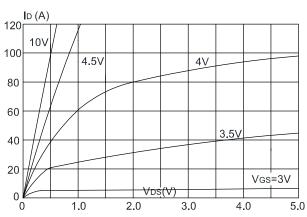


Figure1: Output Characteristics

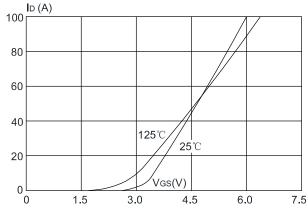


Figure 2: Typical Transfer Characteristics

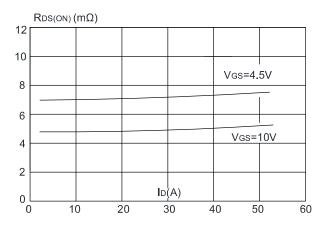


Figure 3:On-resistance vs. Drain Current

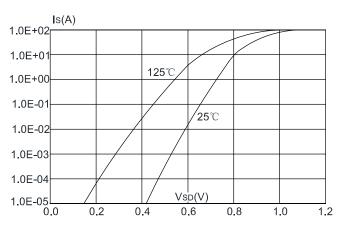


Figure 4: Body Diode Characteristics

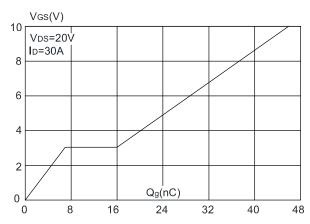


Figure 5: Gate Charge Characteristics

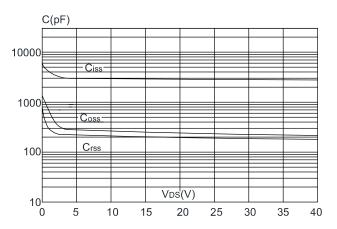
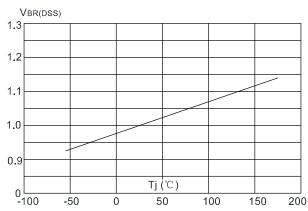


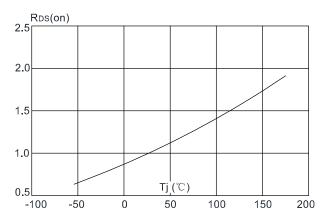
Figure 6: Capacitance Characteristics



## RATING AND CHARACTERISTICS CURVES (RMD50N40DFV)



**Figure 7:** Normalized Breakdown Voltage vs. Junction Temperature



**Figure 8:** Normalized on Resistance vs. Junction Temperature

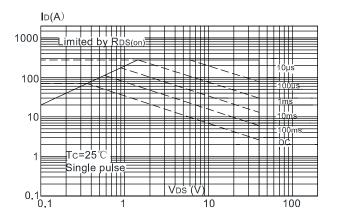
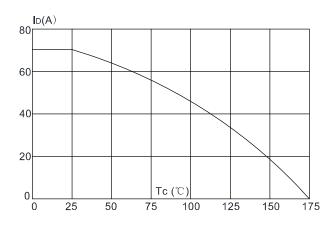
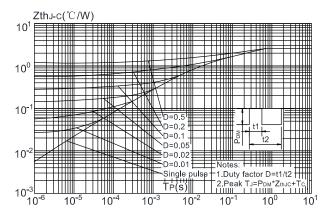


Figure 9: Maximum Safe Operating Area



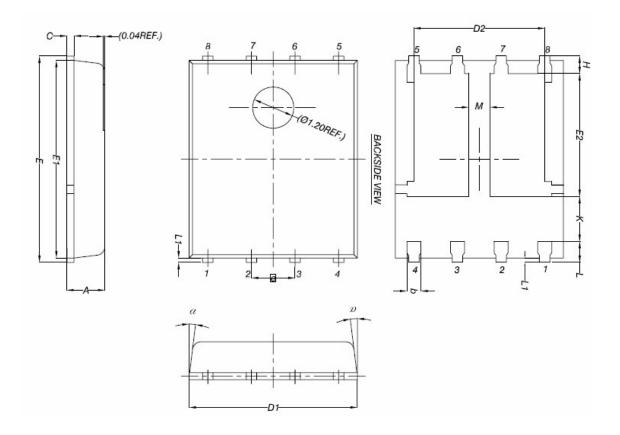
**Figure 10:** Maximum Continuous Drain Current vs Case Temperature



**Figure.11:** Maximum Effective Transient Thermal Impedance, Junction-to-Case



## **DFN5X6-8L Package Information**



	MILLIMETERS			
DIM.	MIN.	NOM.	MAX	
Α	0.90	1.00	1.10	
b	0.33	0.41	0.51	
С	0.20	0.25	0.30	
D1	4.80	4.90	5.00	
D2	3.61	3.81	3.96	
Ε	5.90	6.00	6.10	
E1	5.70	5.75	5.80	
E2	3.38	3.58	3.78	
е	1.27 BSC			
Н	0.41	0.51	0.61	
K	1.10	0.70	-	
L	0.51	0.61	0.71	
L1	0.06	0.13	0.20	
М	0.50	-	-	
α	0°	-	12°	

